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FABRICATION AND CHARACTERIZATION OF Cu-SiC^p COMPOSITES FOR ELECTRICAL DISCHARGE MACHINING APPLICATIONS

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FABRICATION AND CHARACTERIZATION OF Cu–SiCp COMPOSITES FOR ELECTRICAL DISCHARGE MACHINING APPLICATIONS

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ABSTRACT

 $Cu-SiC_p$ composites made by the powder metallurgy method were investigated. To avoid the adverse effect of $Cu-SiC_p$ reaction, sintering was controlled at a reaction temperature less than 1032 K. Electroless plating was employed to deposit a copper film on SiC_p powder before mixing with Cu powder in order to improve the bonding status between Cu and SiC particles during sintering. It was found that a continuous copper film could be deposited on SiC_p by electroless copper plating, and a uniform distribution of SiC_p in Cu matrix could be achieved after the sintering and extrusion process. The mechanical properties of $Cu-SiC_p$ composites with SiC_p contents from 0.6 to 10 wt% were improved evidently, whereas electrical properties remained almost unchanged as compared with that of the pure copper counterpart. In the electrical discharge machining (EDM) test, the as-formed composite electrodes exhibited a character of lower electrode wear ratio, justifying its usage. The optimum conditions for EDM were Cu–2 wt% SiC_p composite electrode operating with a pulse time of 150 µsec.

Key Words: Copper-based composite; Density; Electrical discharge machining; Electrical resistivity; Electrode wear ratio; Electroless copper plating; Fracture surface; Hardness; Material removal rate; Metal matrix composite; Porosity; Powder metallurgy; Silicon carbide; Tensile strength; Thermal expansion coefficient.

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1.0 INTRODUCTION

To machine hard material, such as carbide and molding steel, the electrical discharge machining (EDM) process is often used. In the mold manufacturing industry, the EDM is often used despite its slow machining rate. EDM research has concentrated on achieving faster and more efficient metal removal rate coupled with reducing tool wear and maintaining reasonable accuracy. Recently, tool electrode fabrication became the focus of many studies in EDM technology (1,2), paralleling the development of EDM machine parts such as high-performance generators and adaptive control mechanisms (3,4). The majority of work has been done using a mechanically formed tool electrode; however, because of its economical and technological disadvantages, the EDM user is compelled to search for alternative tooling (5).

Copper and copper-based alloys are widely used in the electrical industry. The addition of ceramic reinforcements such as carbides and oxides to form metal matrix composites (MMCs) enhances the properties such as elastic modulus, strength, wear resistance, and high-temperature durability (6,7). These attractive properties are expected to widen the application of copper composite materials.

At temperatures in excess of 773 K, copper undergoes thermal softening. As a result, a substantial deterioration in its tensile strength and creep resistance takes place (8). There is clearly a need for a copper conductor with electrical conductivity above 80% International Annealed Copper Standard (IACS) and capable of operating above 773 K for a variety of uses, including electrical and resistance welding electrodes (9). Thus, the research in fabricating copper-based composite materials is ongoing, including $Cu-Al₂O₃$, $Cu-Zr-Al₂O₃$, $Cu-TiO₂$, $Cu-Si₃N₄$, $Cu-B₄C$, and $Cu-SiC$ (10–14). Methods for fabricating these composite materials include casting, coprecipitation, internal oxidation, and powder metallurgy (15–20).

Owing to the poor wetting ability and dispersion between copper and reinforcements, the casting methods are impractical. The methods of coprecipitation and internal oxidation are not suitable for mass production, so the powder metallurgy method is the preferred choice.

A nonhomogeneous distribution also occurs when the ceramic powders are incorporated with copper by powder metallurgy, especially when the reinforcements are extremely fine, and when a V-blender or tumble mixer is used (21). The resulting agglomerates lead to unacceptable porosity levels, nonhomogeneous microstructures, and poor interfacial bonding.

A copper film coated on ceramic powder by electroless plating can improve the bonding between ceramic powder and copper powder. The high strength and high electrical conductivity of a copper-based composite can be obtained after sintering when the coated ceramic powder is mixed with copper powder by the mechanical alloying method.

The stability of SiC particles in copper was evaluated by Groza and Gibeling

(22). Their results show that the SiC particle becomes thermodynamically unstable at 1300 K. The result is reasonable because in the Cu–Si–C phase diagram, reported by Warren and Anderson (23), there exists a reacted liquid phase with copper and SiC at 1173 K. Although SiC fiber is reckoned to be decomposed by molten copper at 1356 K and results in the formation of a low-temperature eutectic product according to the Cu–Si–C phase diagram at 1173 K, no reaction was observed between the copper matrix and SiC fiber after a holding time of 3 hr at the melting point of copper (1356 K). However, Qin and Derby (24) showed experimentally that a solid-state reaction occurs between SiC plate and copper deposit at 1173 K. At this temperature, the reaction product of $Cu₃Si$ becomes liquid (melting point 1132 K). Although Groza and Gibeling suggested that the SiC particle is useless for dispersion-strengthened copper alloy (22), for EDM application, the physical properties are as important as the electrical properties of the electrode. Decreasing the harmful factor of physical properties and retaining the virtuous factor of electrical properties enable fabrication of an optimum copper-based EDM electrode.

This paper presents the research aimed at the production of $Cu-SiC_p$ composites by powder metallurgy without solid reaction. This composite is expected to possess high density, high electrical conductivity, and low coefficient of thermal expansion (CTE), and is suitable for EDM usage. The influence of the weight fraction of SiC_p on the mechanical properties was examined. The microstructure and fracture surfaces of composites were observed by optical microscope (OM) and scanning electron microscope (SEM). The two factors of material removal rate and electrode wear ratio on EDM were evaluated to investigate the feasibility of the fabricated $Cu-SiC_p$ electrode material.

2.0 EXPERIMENTAL PROCEDURE

The metal matrix powder used in this experiment was electrolytic copper powder (99.7% pure). The particle morphology was dendritic and average size was 30 μ m. Figure 1 shows the SiC_p powder (average powder size is 4 μ m) used as reinforcements.

To obtain optimal bonding between SiC_p and Cu particles and a completely continuous copper film on SiC_p , the following steps were followed.

2.1 Surface Treatment

Surface cleaning of SiC_p was accomplished by immersing it in acetone under ultrasonic vibration for 30 min. After rinsing well with deionized water, and heating at 873 K for 3 hr in an air-drying oven, the SiC was slightly ground to break agglomerated particles.

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Figure 1. SEM micrograph of SiC_p.

2.2 Sensitization and Activation

The cleaned SiC_p samples were sensitized in a solution containing stanous chloride (SnCl₂⋅2H₂O) and hydrochloric acid (HCl) for 1 hr and then activated in a solution containing palladium chloride $(PdCl₂)$ and hydrochloric acid for a few hours.

2.3 Electroless Copper Process

Before the procedure of mixing, continuous stirring, and rinsing, the cleaned SiC_p was put into CuSO₄ ⋅ 5H₂O (20 g/l) and KNaC₄H₄O₆ (50 g/l) individually, shaken by ultrasound, and then HCOH (36%) and NaOH were added. The pH value of the solution was adjusted by adding NaOH until the pH value approached 13, then the copper film was created. The thick film was obtained by later immersing it in Fehling solution. The components of Fehling solution are as follows: $CuSO_4 \cdot 5H_2O$ (10 g/l); KNaC₄H₄O₆ (25 g/l); HCOH (50 ml/l); and NaOH (7 g/l).

The mixture of the constituent powders with the preselected SiC percentages $(0.6, 2, 4, 6, 8, and 10 wt\%)$ was milled with aluminum balls as the grinding medium in Ar atmosphere, and cold formed by pressing the powders with a unit pressure of 450 MPa.

Specimen ID	Composition of Compact (wt% SiC)	Copper Coating	Extrusion
C1	0.6, 2, 4, 6, 8, 10	Yes	Yes
C ₂	0.6, 2, 4, 6, 8, 10	Yes	No
R ₁	0.6, 2, 4, 6, 8, 10	No	Yes
R ₂	0.6, 2, 4, 6, 8, 10	No	No

Table 1. Specimen Classification

A series of compacts was heated to 1073 K for 4 hr in hydrogen, and then extruded at 973 K by an indirect extrusion method with a 15:1 extrusion ratio. The specimen classifications are summarized in Table 1.

Composite testing involved measurements of the density, hardness, ultimate stress, volume electrical resistivity, and CTE. The density of the $Cu-SiC_p$ composites was measured by using the buoyancy (Archimedes) method. The hardness measurement was performed with a Rockwell hardness tester. Uniaxial tensile testing with a constant cross-head speed of 1.0 mm/min was carried out on a Instron testing machine at room temperature; specimens were machined according to ASTM E8 standard. The four-probe method was used for measuring the electrical resistivity.

The CTE value was obtained using a thermal mechanical analyzer. The products were characterized by means of X-ray diffraction as well as OM, SEM, and transmission electron microscopy (TEM). The particle diameter was measured using a Honeywell UPA particle size analyzer. EDM testing was performed on a Charmer CM30A EDM machine.

3.0 RESULTS AND DISCUSSION

3.1 Change of Powder Particles by Electroless Plating and Milling

Electroless Cu-coated SiC_p samples are shown in Figure 2. The coated copper film is homogenous and continuous. The thickness of the Cu film given in Table 2 was found to be about 0.6 μ m.

Figure 3 shows the X-ray diffraction (XRD) patterns of the treated and the copper-coated SiC_p particles. Figure 3a shows the XRD pattern of SiC_p (which was obtained before adding HCOH and NaOH); the copper tartrate (CuT) and SiC peaks were detected, and no detectable peak appeared for palladium. This is because the concentration of palladium was extremely low and palladium spreads over the surface at the atomic level. After coating, as shown in Fig. 3b, three new peaks appeared at $2\theta = 43.2$, 50.6, and 74.5°. These results indicate that the Cu was coated on the SiC particle.

Figure 4 shows the change in powder–particle morphology of 2 wt% SiC– Cu powder following 8 hr of ball milling. The powder particles underwent re-

Figure 2. SEM micrograph of SiC_p coated with Cu.

Percentile	Uncoated SiC_{n} (μm) Α	Coated SiC_{p} (μm) B	Thickness of Cu Film (μm) $(B-A)/2$
10%	3.442	4.749	0.6535
20%	3.650	4.936	0.643
30%	3.829	5.099	0.635
40%	3.991	5.256	0.6325
50%	4.148	5.413	0.6325
60%	4.321	5.579	0.629
70%	4.494	5.754	0.630
80%	4.732	5.956	0.612
90%	5.129	6.190	0.5305
95%	5.478	6.342	0.432

Table 2. Particle Size of SiC_p Determined Using Honeywell UPA

Figure 3. The XRD patterns of the particles. (a) SiC_p activated with palladium; (b) SiC_p plated with copper.

peated flattening and fracturing as a result of the collisions of the milling balls in the mechanical milling mixture, and consequently became fine powder of flattened particles which look different from the original dendritic shape.

3.2 Density

The true densities obtained by Archimedes' law and the theoretical values are listed in Table 3 for comparison. It was observed that the density of the com-

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Figure 4. The change in powder–particle morphology of 2 wt% SiC_p –Cu for plated samples after 8 hr of ball milling.

posite with electroless copper-plated SiC_p for all wt% SiC_p is a little higher than that without the coating.

The porosity can be determined by the following equation (25):

$$
f_{\rm p} = 1 - \rho/\rho_0 \tag{1}
$$

where f_p is the pore volume fraction, ρ is the measured density, ρ_0 is the theoretical density.

Figure 5. Variation of porosity with SiC_p contents for the Cu–SiC_p composite.

Figure 5 reveals that, compared to the composites made by the extrusion process, all of the composites made by the as-sintering process had relatively high porosity. For the composites made by extrusion, although the porosity increased with increasing SiC_p content, the porosity remained comparatively low.

Figure 6 shows SEM micrographs of polished samples of composites containing 2 wt% SiC_p . The composite made by the as-sintering method (Fig. 6a) contained a large amount of pores, with most of the pores ranging in size from 2 to 40 µm. Some large pores were observed to have flat shapes. However, no large pore was observed in the composite made by the extrusion method (Fig. 6b). In Figure 5, it also can be observed that the porosities of C1 and C2 specimens are slightly lower than those of R1 and R2 specimens individually; this indicated that the density of composites can be improved to a certain extent by coating a copper film on SiC_p . This is presumably caused by better sintering ability between coated SiC–Cu compared to SiC–Cu particles. A hot extrusion process can improve the density of the composites up to 95% of the theoretical density value. As shown in Figure 5, the porosity of the coated 2 wt% SiCp composite significantly decreased following the extrusion process.

3.3 Tensile Strength

The tensile properties of various $Cu-SiC_p$ specimens are given in Table 4. It shows that apparently the tensile properties have been significantly improved through hot extrusion. This is probably because of reduction in the amount and size of the porosity after hot extrusion, interfacial bonding enhancement between

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Figure 6. SEM micrographs of the 2 wt% SiC_p –Cu composites (a) as sintering, and (b) extruded.

SiCp Contents	Specimen	Modulus (Gpa)	0.2% YS (Mpa)	UTS (Mpa)	Elongation $(\%)$
0.6%	C1	81	159	253	5.32
	C ₂	77	151	249	5.28
	R1	71	128	214	5.30
	R2	71	127	208	5.02
2%	C1	83	178	292	4.38
	C2	81	166	268	4.17
	R1	76	125	212	4.32
	R2	72	117	192	3.98
4%	C1	84	175	277	2.41
	C ₂	80	156	260	2.24
	R1	78	113	195	2.31
	R2	77	96	177	2.18
6%	C1	85	138	243	1.86
	C ₂	82	142	237	1.79
	R1	81	103	182	1.84
	R ₂	80	93	173	1.76
8%	C1	86	132	229	1.53
	C ₂	84	130	214	1.31
	R1	83	104	168	1.32
	R2	79	101	158	1.29
10%	C1	86	124	210	1.44
	C ₂	85	119	202	1.41
	R1	84	90	155	1.42
	R ₂	81	87	150	1.28

Table 4. Tensile Test Results

SiC and the matrix, grain reinforcement of Cu matrix, and a more homogeneous distribution of SiC after hot extrusion. The wt% of SiC_p and the electroless plating process were found to tremendously influence the tensile property of copper matrix composite. Figure 7 demonstrates that ultimate stress decreases with an increasing amount of uncoated SiC_p . There is a maximum value of ultimate stress at 2 wt% if the SiC_p particles are electroless plated with copper. This phenomenon is caused by particle reinforcement. The strength of composite decreases if the SiC_p is increased, because more defects are produced. The tensile strength of composites with uncoated SiC_p is lower than the composites with electroless-plated SiC_p . The strength of the composite is reduced by the presence of SiC_p owing to the poor bonding between the uncoated SiC_p and copper.

3.4 Hardness

Figure 8 shows the change in the Rockwell hardness number of $Cu-SiC_p$ composites for various SiC_p wt% made by various methods. The hardness value increases with increasing SiC_p wt%. Generally, the hardness of material increases

Figure 7. The ultimate stress in $Cu-SiC_p$ composites.

with increase of material strength. However, in the present work, the strength decreased with increasing SiC_p wt% (Fig. 7). As can be seen in Figure 5, the porosity increases with increasing SiC_p wt%; this is responsible for the corresponding decreasing stress and increasing hardness tendencies (Figs. 7 and 8, respectively). The former tendency has been explained in section 3.3. The latter

Figure 8. The Rockwell hardness number of $Cu-SiC_p$ composite.

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increasing hardness tendency is qualitatively explained as follows: the $Cu-SiC_p$ hardness is probably determined by the composite effect of porosity and SiC particles. It is apparent that the Cu–SiC interface increases with increasing $SiC_p wt\%$, thus hindering more seriously the Cu slipping and resulting in increased hardness. In this work, the pore sizes were only about one-half to one-third of SiC_p sizes (Fig. 6) and the porosity increased only mildly with SiC_p (Fig. 5). Therefore, the effect of porosity on hardness would appear much less important than the dominant effect of Cu/SiC interface (i.e., the inherent high SiC hardness).

The promoted bonding between SiC_p and Cu by copper-coating method restrains more effectively elastic and plastic deformation of the composites, leading to higher hardness. Much lower porosity can be achieved through the extrusion process, rendering higher composite hardness.

3.5 Fracture Surface

SEM micrographs of the fracture surfaces of the composites with 0.6 wt% uncoated SiC_p content having poor interface bonding between the matrix and the particle is shown in Figure 9a. SiC_p shows relatively flat surfaces, and a sample with 2 wt% coated SiC_p content (where the copper film can be seen on the surface of SiC_p) is shown in Figure 9b. In both samples, fracture appears to initiate at the SiC_p particles, with the fracture surfaces characterized by the presence of large microvoids with SiC_p particles at the center of each dimple. The crack may propagate along the interface between SiC_p particles and matrix, and within SiC_p particles. In addition to the normal ductile dimple fracture of the matrix, there are two types of fracture behavior involved with SiC_p particulate: fracture of SiC_p and Cu– SiC_p interface decohesion. In Figure 9a, the fracture surface shows the presence of decohesion at the Cu–SiC_p interface. However, the occurrence of SiC_p fracture was observed in Figure 9b, and this indicates that there was load transfer from the matrix to the SiC_p particulate.

3.6 Electrical Resistivity

The electrical resistivity of composites depends on the size and number of microweldments developed between particles during sintering. Figure 10 indicates that the electrical resistivity is increased with a higher SiC_p content.

The effective electrical resistivity σ_{eff} of two-phase composite materials can be determined by the simple rule of mixture (ROM) when the electrical resistivity of both phases are comparable, i.e., $\sigma_1 \sim \sigma_2(26)$, and

$$
\sigma_{\rm eff} = f_1 \times \sigma_1 + f_2 \sigma_2 \tag{2}
$$

where f_i is the volume fraction and σ_i is the electrical resistivity of phase *i*.

 $5.8cm$ $x\ddot{o}$: $\ddot{o}\dot{o}\dot{k}$ 670295 20KV **(b)**

Figure 9. SEM micrographs of the fracture surface of composites in (a) 0.6% uncoated SiC_p, and (b) 2 wt% coated SiC_p .

Figure 10. Measured and predicted electrical resistivity of $Cu-SiC_p$ composites.

The σ_{eff} value is 166,001 µ Ω -cm if the ROM model is used to calculate the effective electrical resistivity of composite with 0.6 wt% of SiC_p content, and a large discrepancy from experiment data was found.

When the difference between electrical resistivity of constituent phases is increased, the dependence of the effective resistivity on the volume fraction becomes nonlinear, and the electrical resistivity can be represented by the effective medium theory (EMT). EMT considers a spherical entity consisting of a single phase embedded in the surrounding effective medium, with the following relation given in reference 27:

$$
f_1 \times \frac{\sigma_1 - \sigma_{\text{eff}}}{\sigma_1 + 2\sigma_{\text{eff}}} + f_2 \times \frac{\sigma_2 - \sigma_{\text{eff}}}{\sigma_2 + 2\sigma_{\text{eff}}} = 0
$$
\n(3)

where the surface electrical resistivity of copper and SiC_p are 1.130 and 1.0 \times $10^7 \mu\Omega$ cm, respectively. The electrical resistivity of the copper composite calculated by the above model gives close results to the experimental data shown in Figure 10.

3.7 CTE

Because the CTEs for Cu and SiC_p are 16.9×10^{-6} K⁻¹ (293–573 K) and 5.0×10^{-6} K⁻¹, respectively (28,29), it is expected that the CTE of the composite would be lowered with the addition of SiC_p . The CTE of a particle-reinforced composite is often estimated by three popular models (30), for which the ROM model is often considered inappropriate because it does not take into account

the microstructure and strain interactions. The Turner's model (31), considering uniform hydrostatic stresses exit in the phases, predicts the CTE of a composite by

$$
\alpha_{\rm c} = \frac{\alpha_{\rm p} f_{\rm p} k_{\rm p} + \alpha_{\rm m} f_{\rm m} k_{\rm m}}{f_{\rm p} k_{\rm p} + f_{\rm m} k_{\rm m}} \tag{4}
$$

where α_c , α_p , and α_m are the CTEs of composites, reinforcements, and matrix, respectively; k_m is the bulk modulus of matrix; and the Kerner's model (32) accounts for both the shear and isostatic stress developed in the component phases and determines the composite CTE by

$$
\alpha_{\rm c} = \alpha_{\rm p} f_{\rm p} + \alpha_{\rm m} f_{\rm m} + (\alpha_{\rm p} - \alpha_{\rm m}) f_{\rm p} f_{\rm m} \frac{k_{\rm p} - k_{\rm p}}{k_{\rm p} f_{\rm p} + k_{\rm m} f_{\rm m} + \frac{3k_{\rm p} k_{\rm m}}{4G_{\rm m}}}
$$
(5)

where G_m is the shear modulus of matrix.

The measured and calculated results of linear thermal expansion curves for $Cu-SiC_p$ composite are presented in Figure 11. The results show that the CTE decreases as the SiC_p weight fraction increases. The experimental CTEs are much higher than these predictions. The results reflect the weak bonding between SiC_p and Cu, which provides little constraint on the expansion or contraction of the copper matrix.

Figure 11. Measured and predicted linear thermal expansion of the $Cu-SiC_p$ composites (200– 500°C).

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3.8 Material Removal Rates on EDM

Metal removal rate is an important parameter for evaluating the machining performance of EDM for a particular working setup, and the machining rate depends on the electrode manufacturing variable. Material removal rate can be expressed as follows (33):

$$
W_{\rm m} = K_{\rm m} \cdot \tau_{\rm on}^a \cdot I_{\rm p}^b \cdot \frac{10^6}{\tau_{\rm on} + \tau_{\rm off}} \tag{6}
$$

where W_m is the material removal rate (mm³/min); K_m , *a*, and *b* are coefficients to be determined by test condition; and τ_{on} and τ_{off} (in µsec) are pulse on time and pulse off time, respectively.

A higher discharge current leads to higher discharge energy and energy density. Thus, more material can be melted which increases the removal rate. Figure 12 shows that the material removal rate increases with an increase in applied current. In general, the removal rate varies very little under the normal condition of pulse off time. The pulse on time is taken to be 150μ sec in this research, so the material removal rate increases with the increase of applied current. The maximum removal rate was found for Cu–2wt% SiC_p composite. This suggests that EDM with 2 wt% SiC_p of copper electrode is the better choice for cutting mold steel when pulse time is 150 µsec.

Figure 12. Relationship of the material removal rate, applied current, and SiC_p wt%. ($\tau_{on} = 150$ μsec; τ_{off} = 150 μsec; positive electrode; SKD61 workpiece.)

<i>Lable</i> 5. Ine Product of A and I_m						
Material	Fusion Temperature $T_{\rm m}$ (K)	Thermal Conductivity $\lambda(w/mk) \times 10^4$	$\lambda \times T_{m}(w/m)$			
Cu	1357	369	40.0			
SiC_p	2473	67	14.7			

Table 5. The Product of λ and T_m

3.9 Electrode Wear Ratio

An ideal EDM tool electrode is the one that not only can remove a large amount of material from the workpiece, but also is capable of resisting self-erosion.

Table 5 shows the fusion temperature and thermal conductivity (λ) for Cu and SiC_p . The electrode wear is roughly proportional to the product of thermal conductivity (λ) and fusion temperature (T_m) (34). Although the fusion temperature of SiC_p is high, because its thermal conductivity is very small, the product of thermal conductivity and fusion temperature ($\lambda \times T_{\text{m}}$) for SiC_p is less than that for Cu, so the ($\lambda \times T_{\text{m}}$) values for the composite are decreased by increasing SiC_p wt%.

The electrode wear *P* is affected by the discharge pulse energy, which is determined by discharge current and pulse on time, as shown in the following formula (32):

Figure 13. Relationship of the tool wear ratio, applied current, and SiC_p wt% ($\tau_{on} = 150$ µsec; $\tau_{\text{off}} = 150$ µsec; positive electrode; SKD61 workpiece.)

Cu–SiC_p COMPOSITES 501

$$
P = \int_0^{\tau_{\rm on}} u(t) \mathrm{d}t \tag{7}
$$

where $u(t)$ is the discharge voltage in V; $i(t)$ is the discharge current in A; and τ_{on} is the pulse on time in usec. This formula indicates that the increase of discharge current and pulse on time increases the discharge pulse energy as well as the electrode wear.

The variations of tool wear ratio of the electrode with various SiC_p wt% operating at different currents are shown in Figure 13. In general, the tool wear ratio is proportional to the applied current. As discussed above, the higher discharge current leads to higher energy, thus both the material removal rate and tool wear ratio are increased. It also can be observed that the tool wear ratios are almost the same when SiC_p contents are under 4 wt%, and they increase dramatically when SiC_p contents are larger than this value. The $\lambda \times T_{\text{m}}$ value of composite was decreased by increasing SiC_p contents, leading to increased wear ratio with increasing SiC_p contents.

4.0 CONCLUSIONS

The mechanical properties of Cu/SiC_p metal–matrix composite, made by powder sintering and extrusion, can evidently be improved from the pure copper counterpart. This is due to the strengthening effect of SiC powder dispersed into the Cu matrix. It was found that an improved bonding could be achieved by activation of SiC powder surface through electroless coating of Cu onto SiC powder.

From the results of the present work, it was found that a continuous copper film coated on SiC_p by electroless copper coating to form a uniform distribution of SiC_p in Cu matrix is possible. A lower electrode wear ratio can be achieved for EDM testing, and the 2 wt% SiC_p of copper electrode is the better choice for cutting mold steel when pulse time is 150 µsec.

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